TOSHIBA Field Effect Transistor Silicon N-Channel MOS Type (π -MOS V)

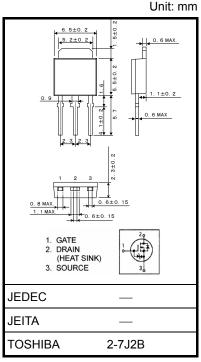
2SK4022

Switching Regulator, DC/DC Converter and Motor Drive Applications

- 4 V gate drive
- Low drain-source ON-resistance: R_{DS (ON)} = 1.2 Ω (typ.)
- High forward transfer admittance: |Y_{fs}| = 2.2 S (typ.)
- Low leakage current: I_{DSS} = 100 μA (V_{DS} = 250 V)
- Enhancement mode: $V_{th} = 1.5 \sim 3.5 \text{ V} (V_{DS} = 10 \text{ V}, I_D = 1 \text{ mA})$

Absolute Maximum Ratings (Ta = 25°C)

Characteristic		Symbol	Rating	Unit
Drain-source voltage		V _{DSS}	250	V
Drain-gate voltage ($R_{GS} = 20 \text{ k}\Omega$)		V _{DGR}	250	V
Gate-source voltage		V _{GSS}	±20	V
Drain current	DC (Note 1)	Ι _D	3	
	Pulse (t = 1 ms) (Note 1)	I _{DP}	6	A
Drain power dissipation (Tc = 25° C)		PD	20	W
Single-pulse avalanche energy (Note 2)		E _{AS}	36.2	mJ
Avalanche current		I _{AR}	3	А
Repetitive avalanche energy (Note 3)		E _{AR}	2	mJ
Channel temperature		T _{ch}	150	°C
Storage temperature range		T _{stg}	-55~150	°C



Weight: 0.36 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Characteristics

Characteristic	Symbol	Мах	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	6.25	°C/W
Thermal resistance, channel to ambient	R _{th (ch-a)}	125	°C/W

Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2: $V_{DD} = 50 \text{ V}, \text{ T}_{ch} = 25^{\circ}\text{C}, \text{ L} = 6.7 \text{ mH}, \text{ I}_{AR} = 3 \text{ A}, \text{ R}_{G} = 25\Omega$

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Handle with care.

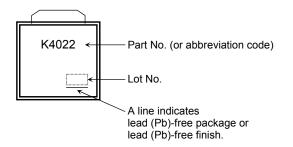
Electrical Characteristics (Ta = 25°C)

Char	acteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	rrent	I _{GSS}	$V_{GS}=\pm 16~V,~V_{DS}=0~V$		—	±10	μA
Drain cutoff curre	ent	I _{DSS}	$V_{DS} = 250 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$		_	100	μA
Drain-source bre	akdown voltage	V (BR) DSS	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	250	_		V
Gate threshold v	oltage	V _{th}	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 1 \text{ mA}$	1.5	_	3.5	V
Drain-source ON	-resistance	R _{DS (ON)}	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 1.5 \text{ A}$		1.2	1.7	Ω
Forward transfer	admittance	Y _{fs}	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 1.5 \text{ A}$	0.5	2.2		S
Input capacitance	e	C _{iss}			267		
Reverse transfer capacitance		C _{rss}	$V_{DS} = 10 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ f} = 1 \text{ MHz}$	_	32	_	pF
Output capacitance		C _{oss}			98		
Switching time	Rise time	tr	$10 V$ V_{GS} $0 V$ 4.7Ω $V_{DD} = 1.5 A$ V_{OUT} $R_{L} = 67 \Omega$ $V_{DD} = 100 V$	_	5		
	Turn-on time	t _{on}			20		- ns
	Fall time	t _f		_	5		
	Turn-off time	t _{off}			30	_	
Total gate charge		Qg			12		
Gate-source charge		Q _{gs}	V _{DD} ≒200 V, V _{GS} = 10 V, I _D = 3 A	_	6		nC
Gate-drain charge		Q _{gd}]	_	6	_	

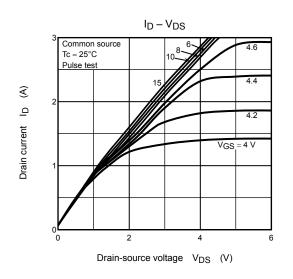
Source-Drain Ratings and Characteristics (Ta = 25°C)

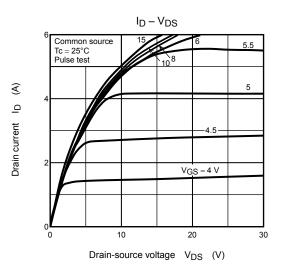
Characteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	—	_	_	3	А
Pulse drain reverse current (Note 1)	I _{DRP}	—	_	_	6	А
Forward voltage (diode)	V _{DSF}	$I_{DR} = 3 \text{ A}, V_{GS} = 0 \text{ V}$	_	_	-2.0	V
Reverse recovery time	t _{rr}	$I_{DR} = 3 \text{ A}, V_{GS} = 0 \text{ V},$	_	125	_	ns
Reverse recovery charge	Q _{rr}	dl _{DR} /dt = 100 A/µs	_	470	_	nC

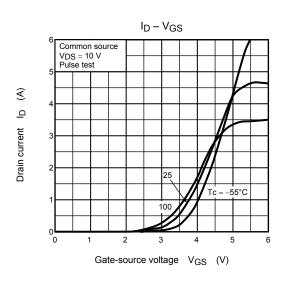
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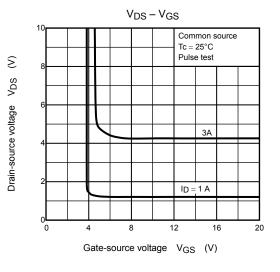


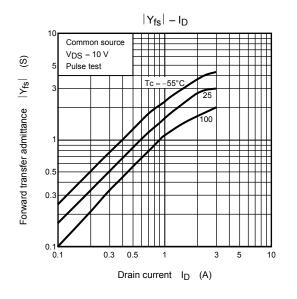
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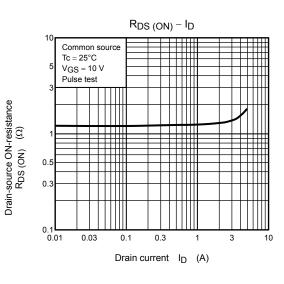




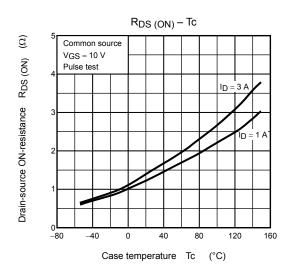


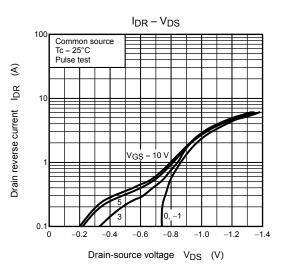


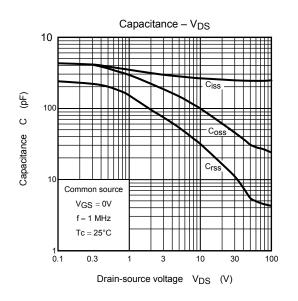


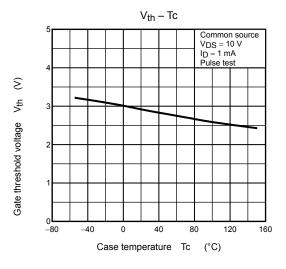


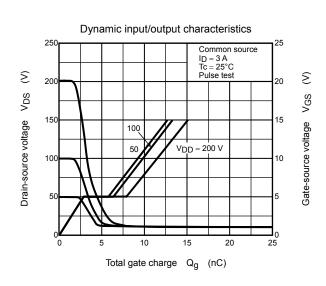
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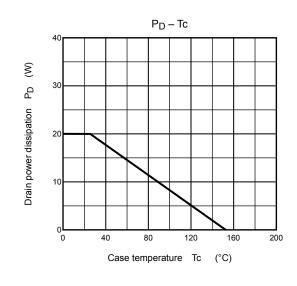


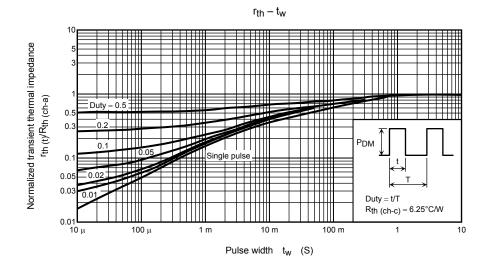




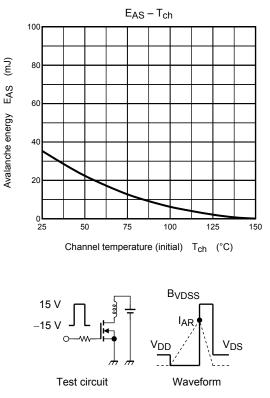








Safe operating area 100 50 30 10 ID max (pulsed) * ID max (continuous) 100 µs Ð ₽ Drain current DC 0.5 0.3 0.1 * Single nonrepetitive pulse 0.05 $\text{Tc}=25^{\circ}\text{C}$ 0.03 Curves must be derated linearly with increase in temperature. /DSS ma: 0.01 35 10 30 50 100 300 500 1000 1 Drain-source voltage V_{DS} (V)



$R_G = 25 \Omega$	$E_{AS} = \frac{1}{2} \cdot L \cdot l^2 \cdot \left(\frac{1}{2} \cdot L \cdot l^2 \cdot L \cdot l^2 \cdot L \cdot l^2 \cdot L \cdot l^2 \cdot L \cdot $	BVDSS	
$V_{DD} = 50 \text{ V}, \text{ L} = 6.7 \text{ mH}$	= A3 2 - (BVDSS-VDD	

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